

**Oscilloscope**

Osc. Active

Channel 1

Manual

Save

Button is clicked to activate oscilloscope or show graph at memory

To catch the last signal automatically

**Synchronous**

Channel 1

Up

**1. Channel**

Probe X1

Top Value : 2,98 V

Low Value : -0,02 V

Point :

Frequen. : 1,6 KHz

Position of probe's switch: X 1 or X 10

Ch.1 Input signal values

**2. Channel**

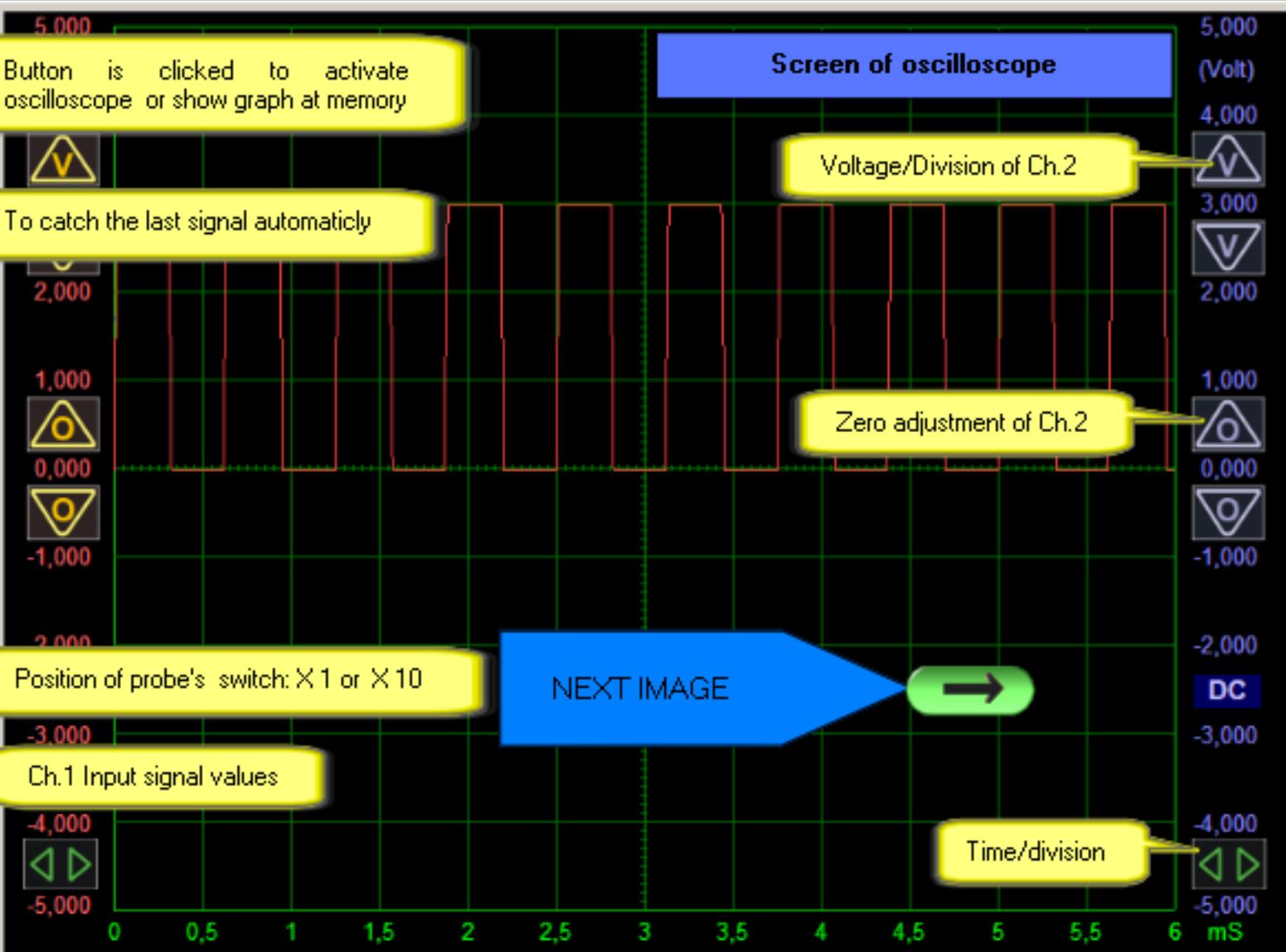
Probe X1

Top Value : 0,00 V

Low Value : 0,00 V

Point :

Frequen. :



ATTENTION: Chassis to connect to the point must be isolated or grounded. ADVICE: Use Probe is 10X position.

**Analog Output (Channel 2)**

Active

Ch.2 activates output signal

Frequency : 1600

Voltage mV: 3000

**Design**

Signal

DAC



Test:

**Channel 1 - 2**

Automatic

1 V  
2 V  
5 V  
10 V

Very Low Frk.  
Low 2 Frk.  
Lov 1 Frk.  
Test Frk.  
H Frk (5-10V)

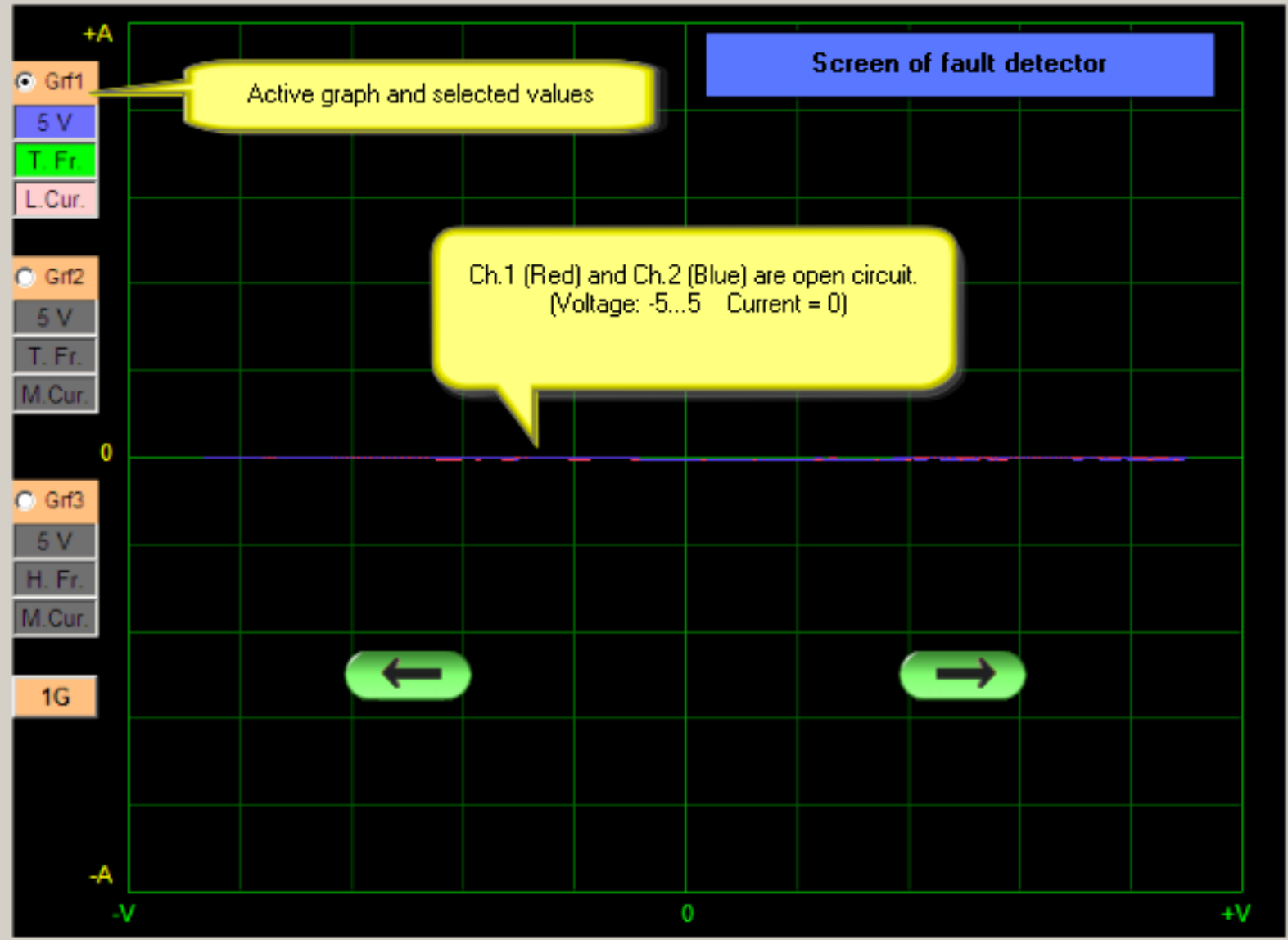
L. Current (47K)  
M. Current (2K7)  
H. Current (550)

Compare  
 Capasite Test  
 T.T.T. FET IGBT

Memory Save - Test

**Recording**

Tolerance (%)



ATTENTION: Probe must be at 1X position. High-voltage capacitors must be emptied by using a resistor.

Reference: Ch1 —

Open Circuit

Test: Ch2 —

Open Circuit

Click to display fault detector screen

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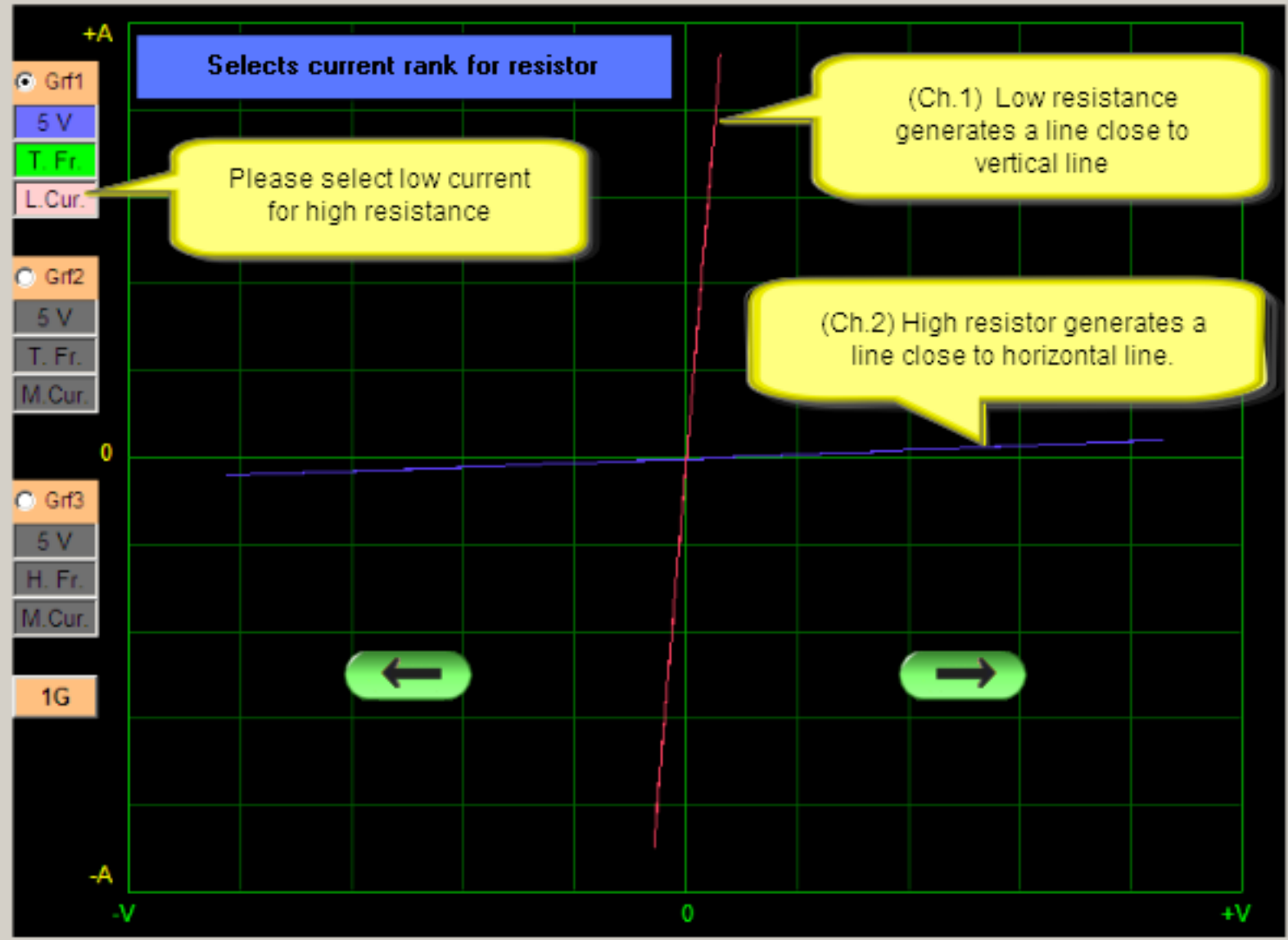
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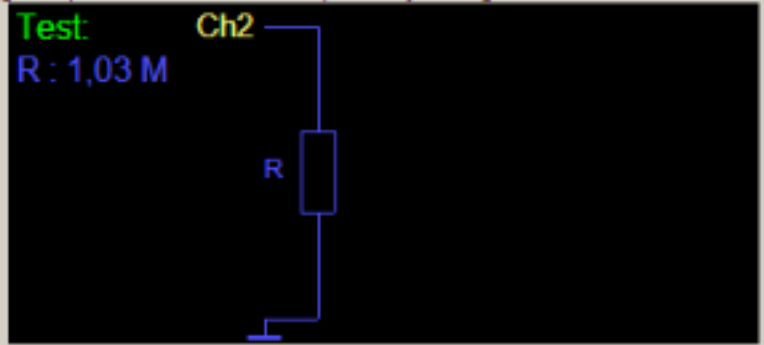
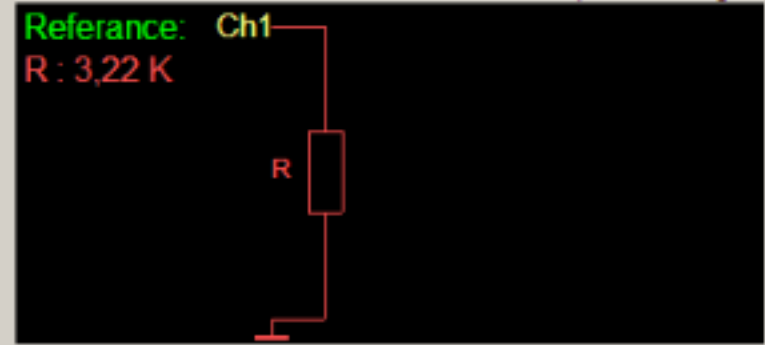
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Tolerance (%) **3**



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OSCILLOSCOPE - ANALOG OUTPUT

FAULT DETECTOR - VI TESTER

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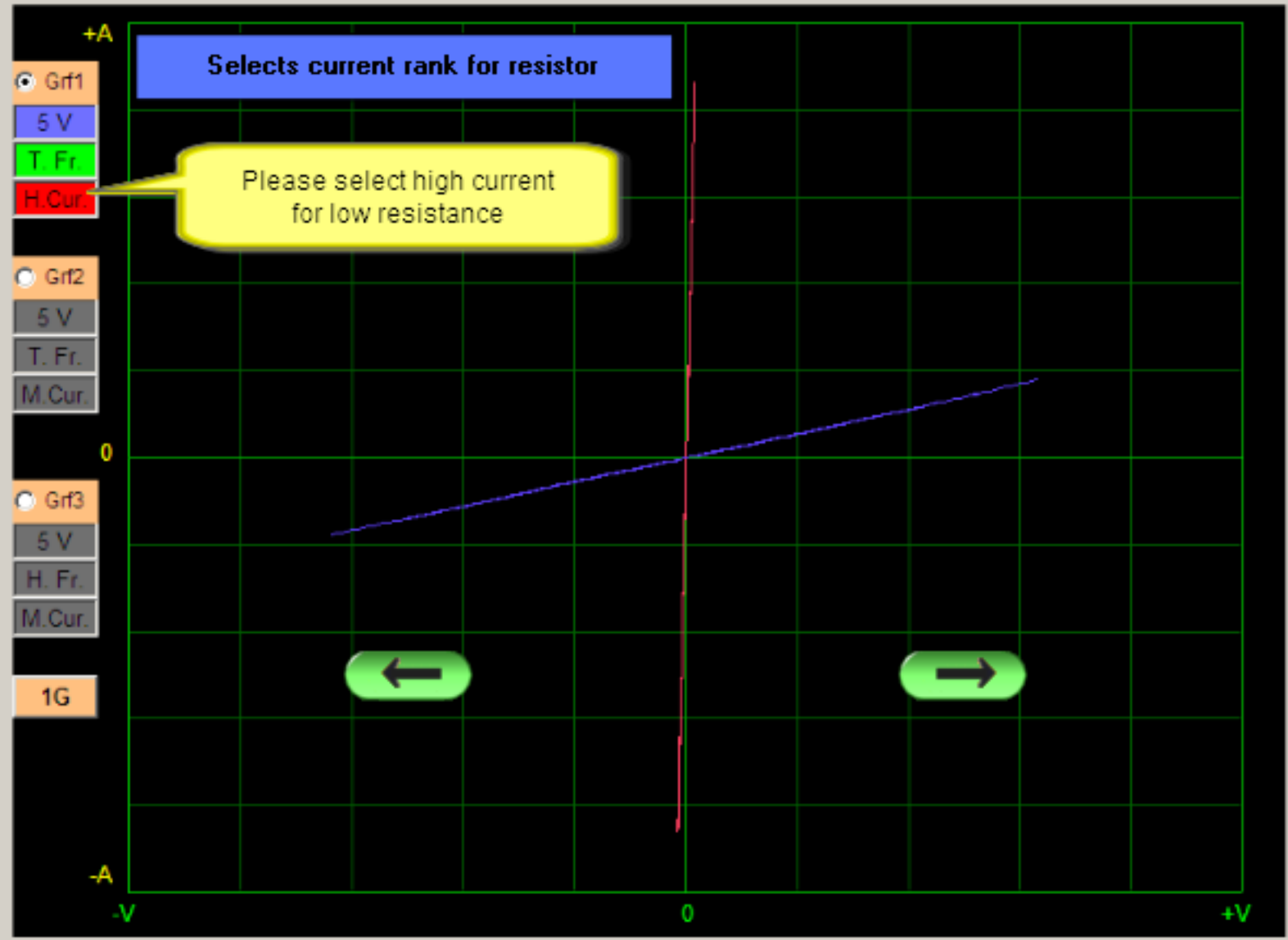
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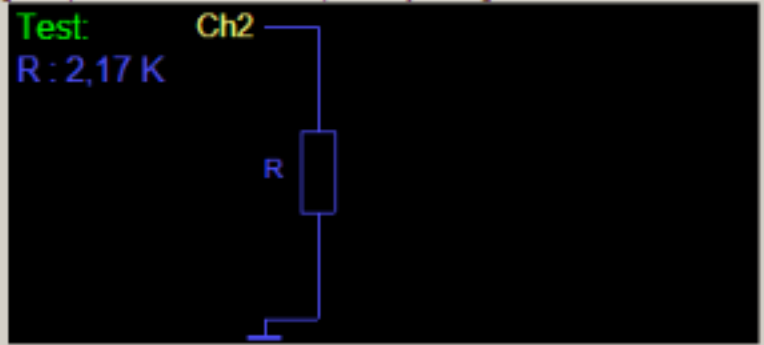
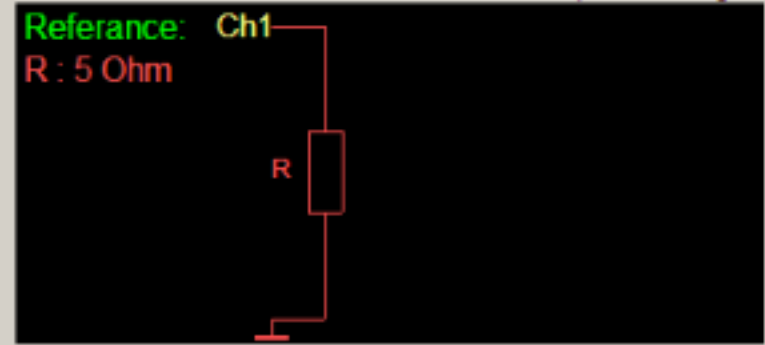
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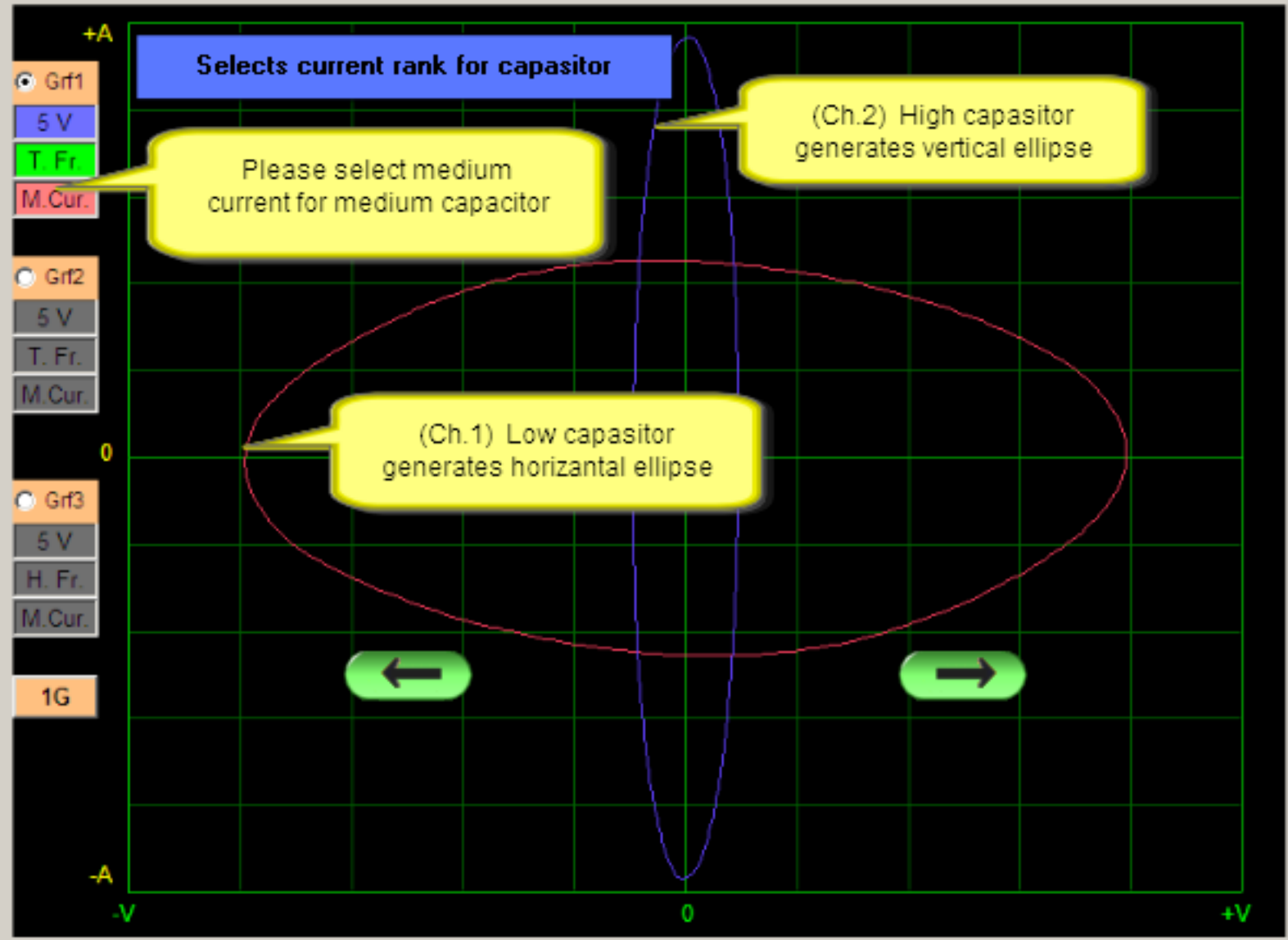
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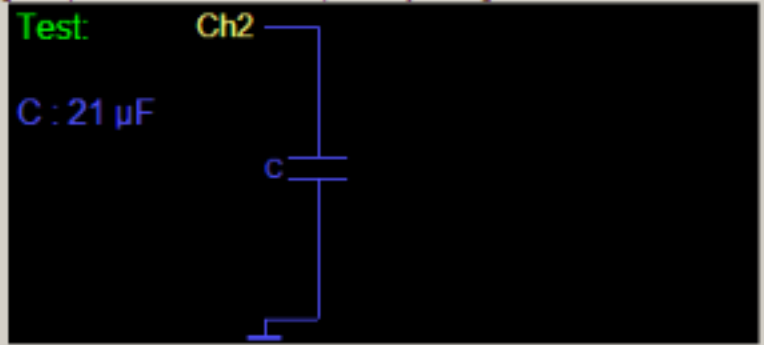
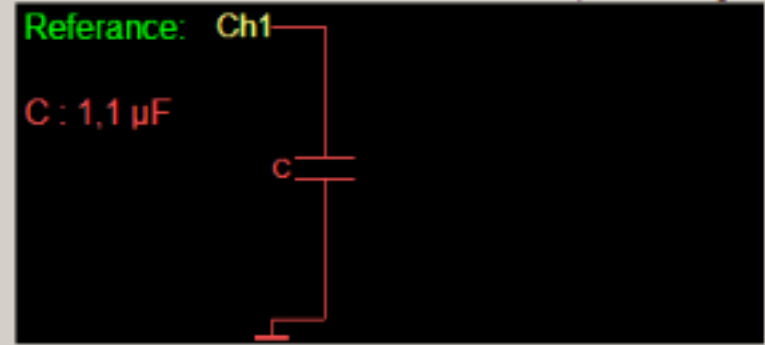
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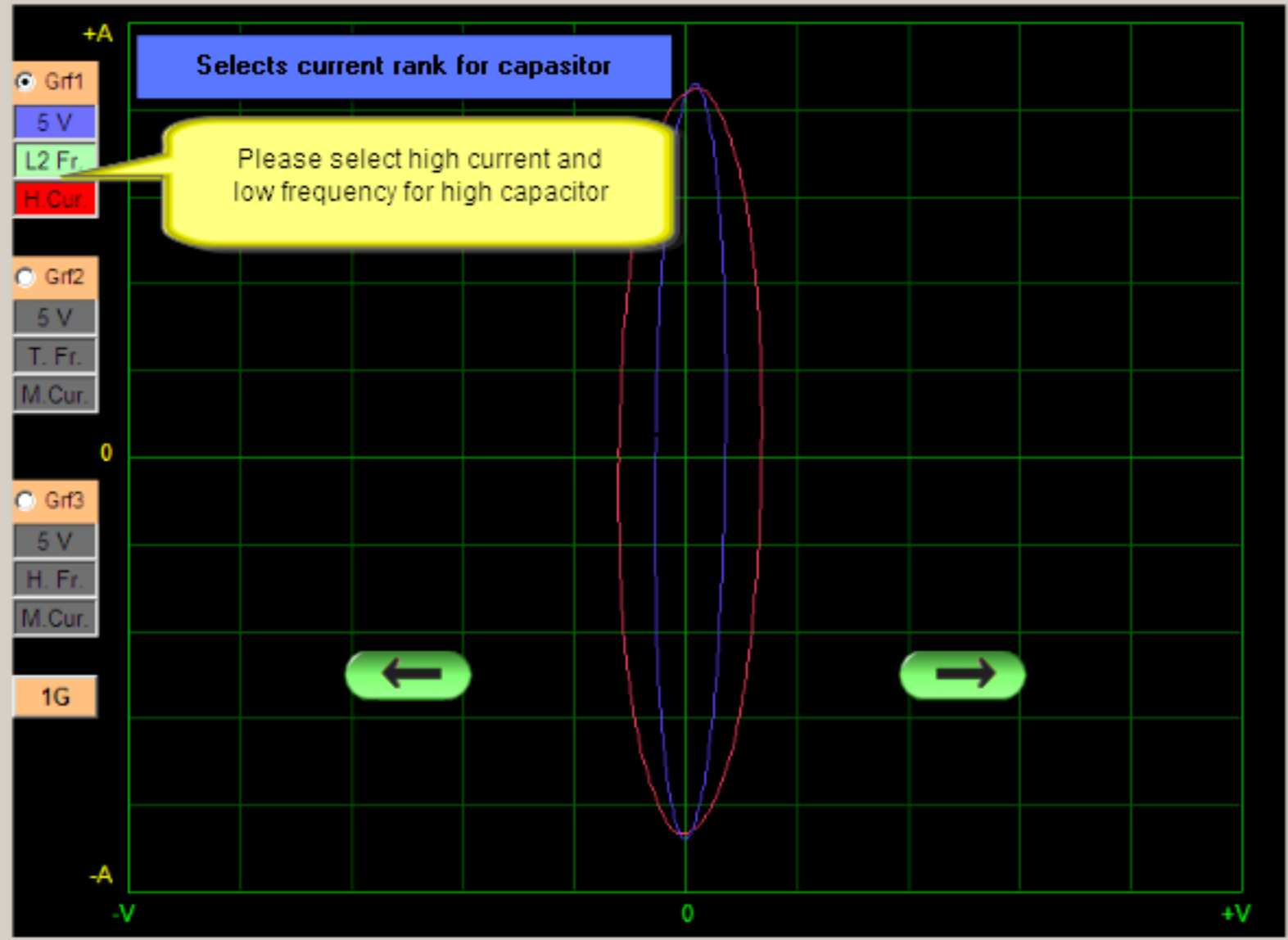
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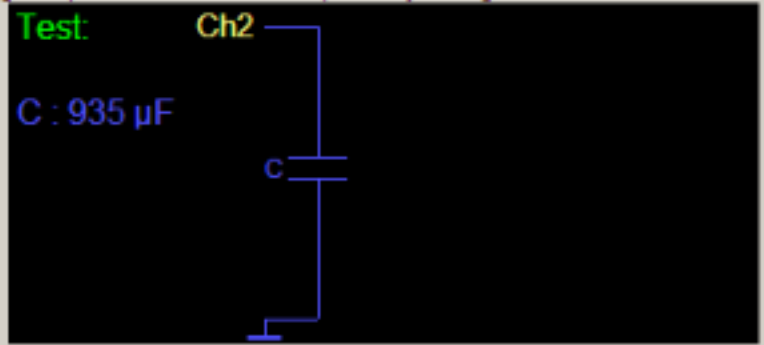
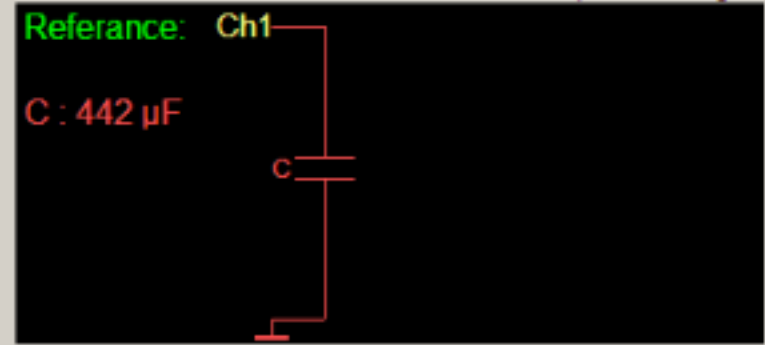
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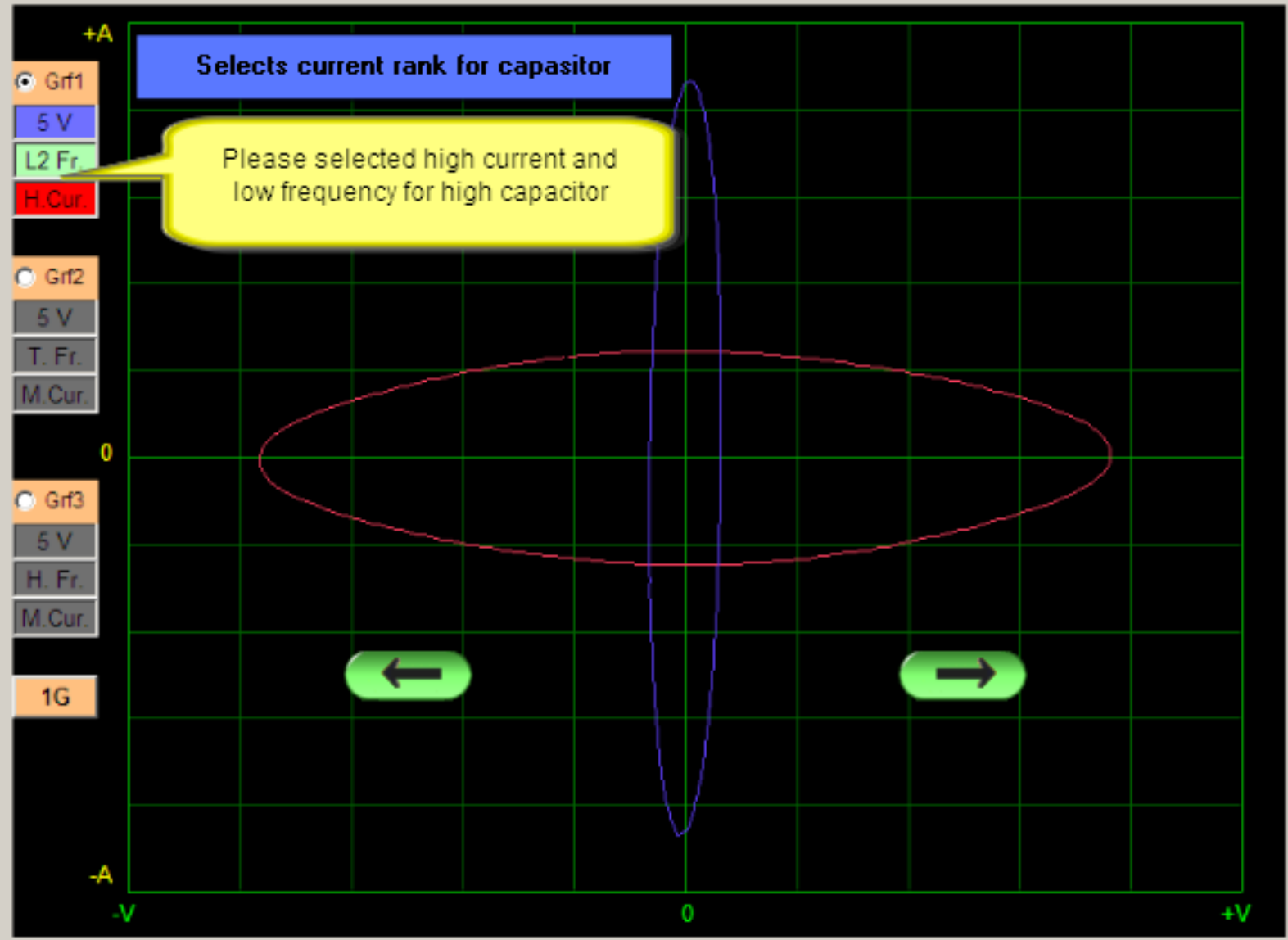
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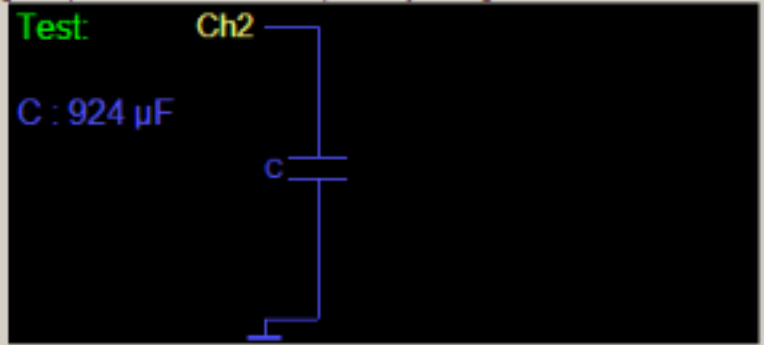
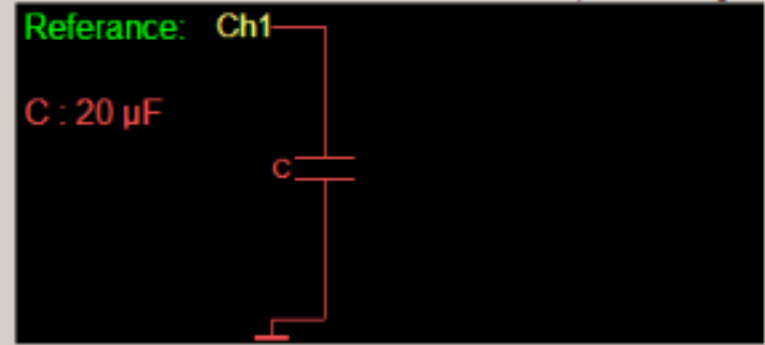
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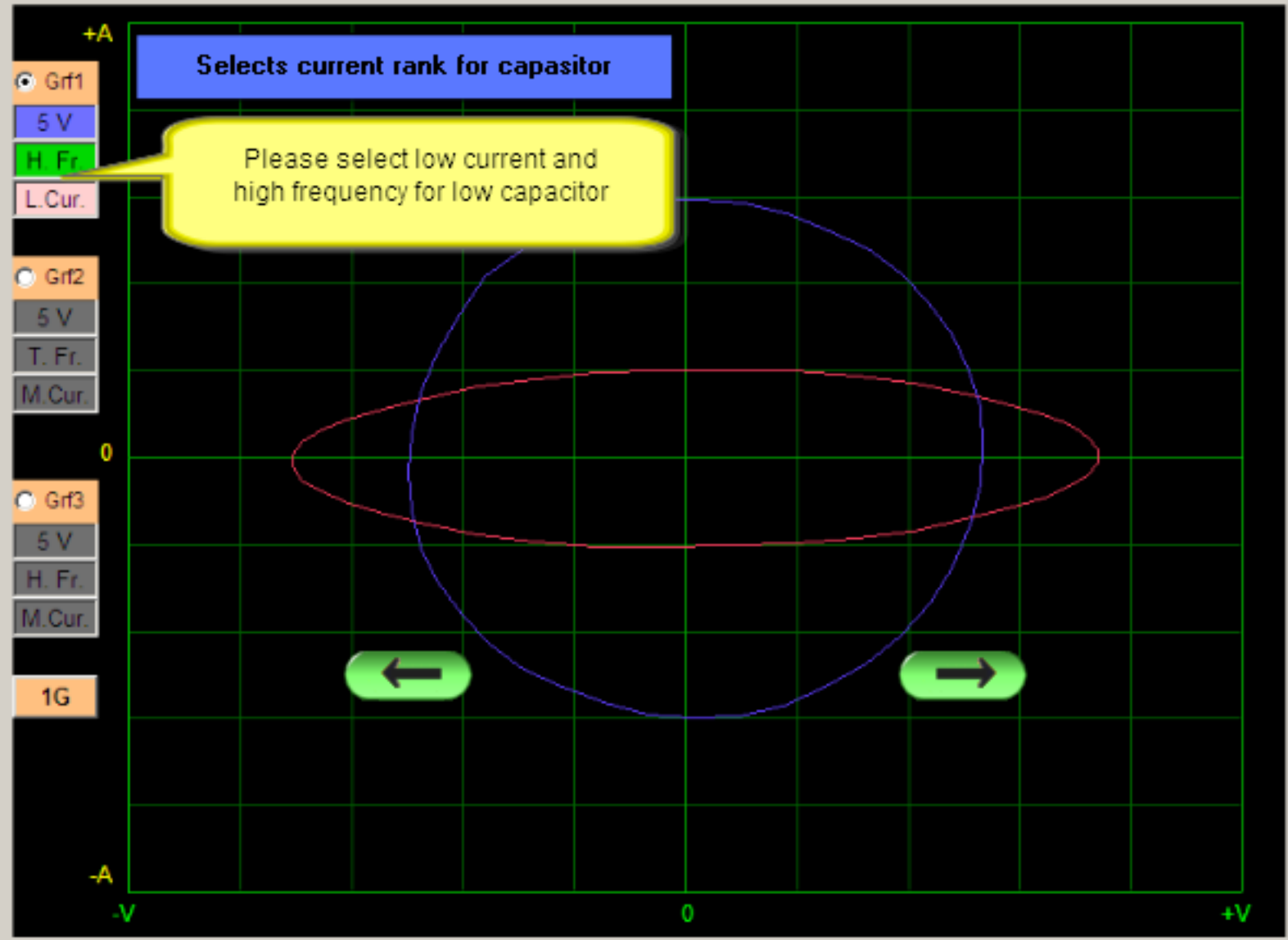
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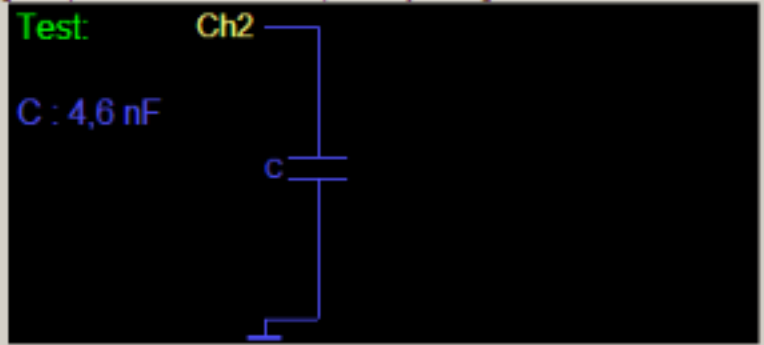
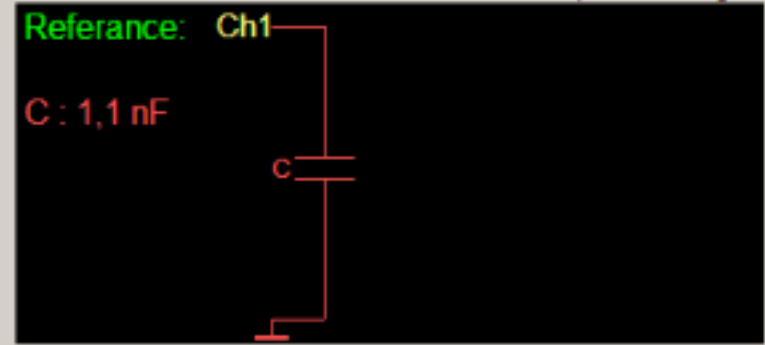
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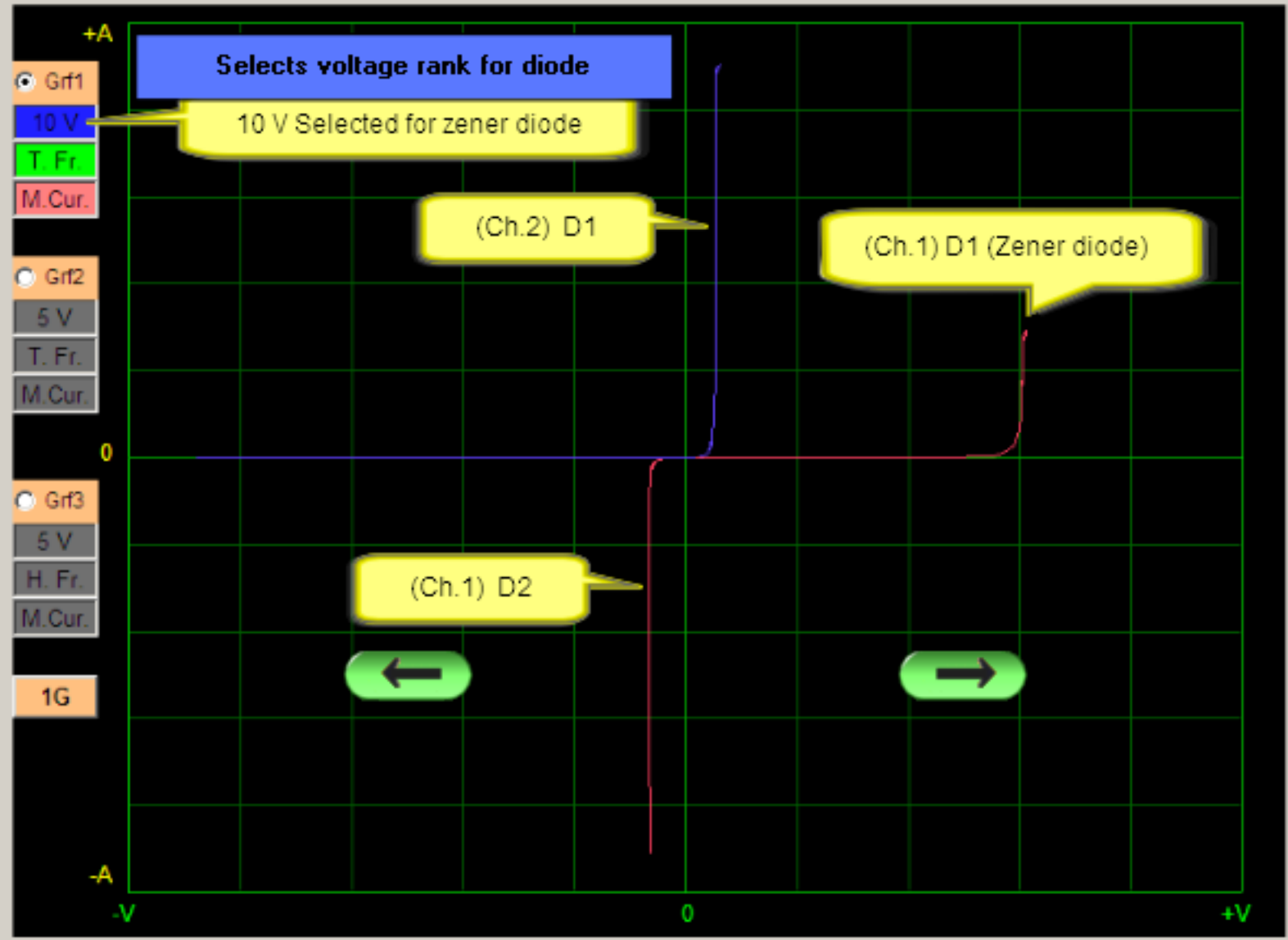
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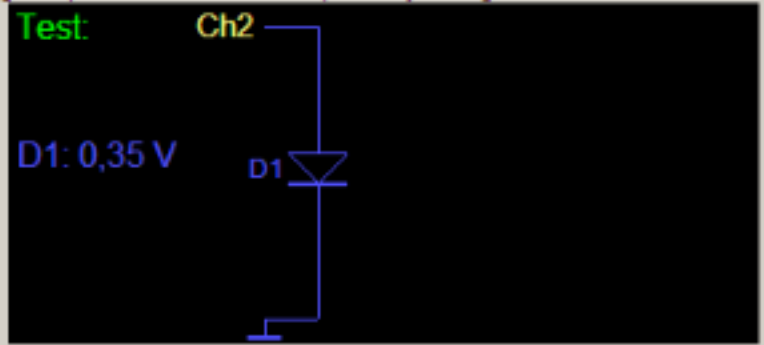
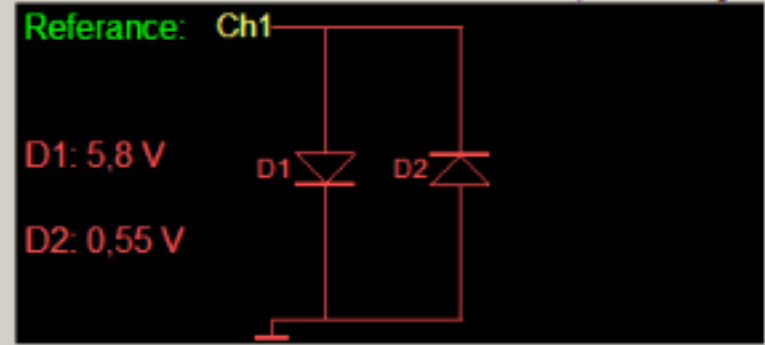
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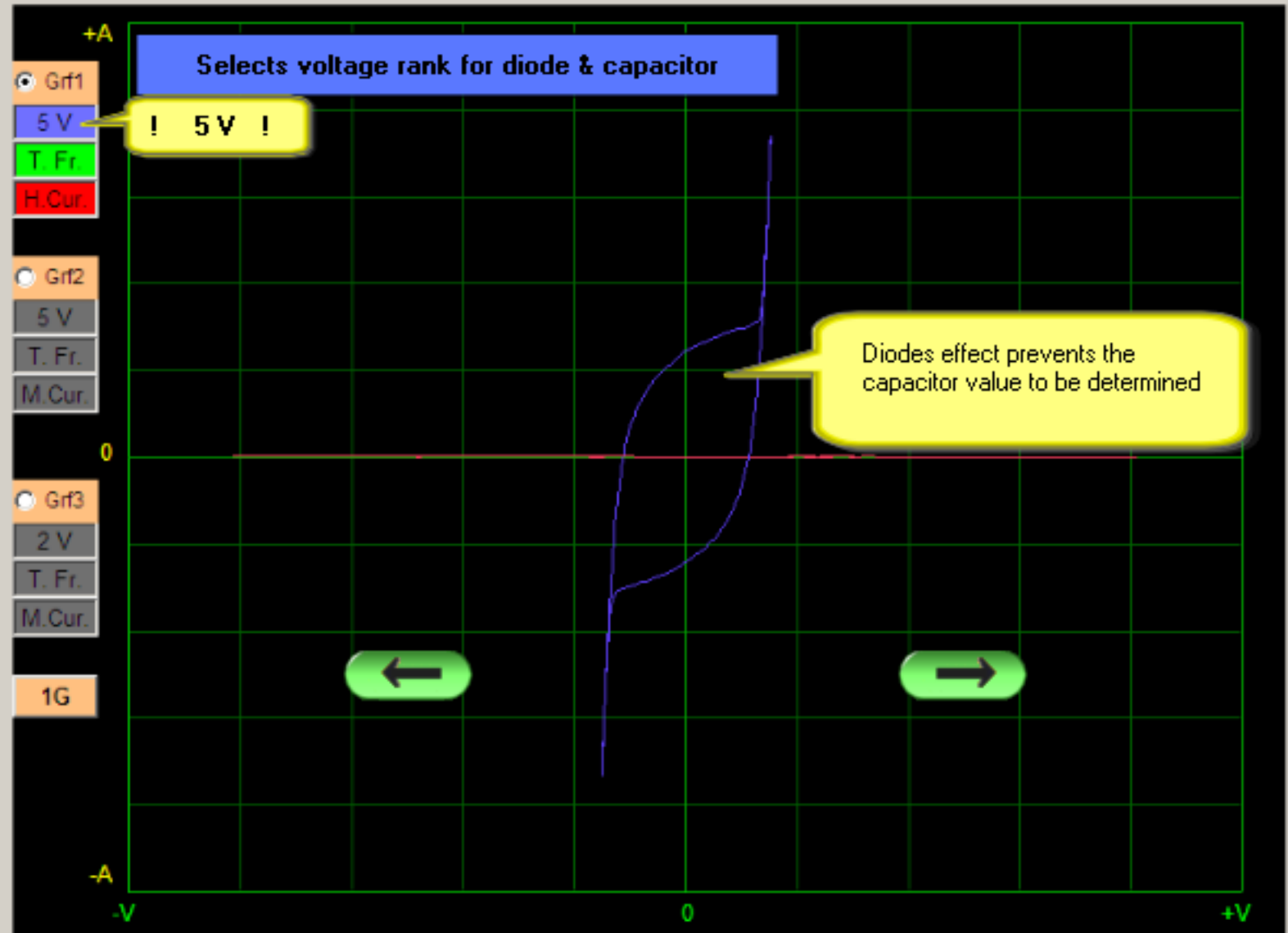
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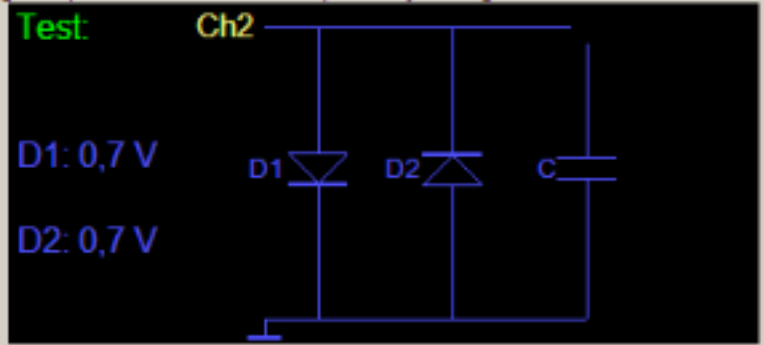
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Reference: Ch1 —

Open Circuit



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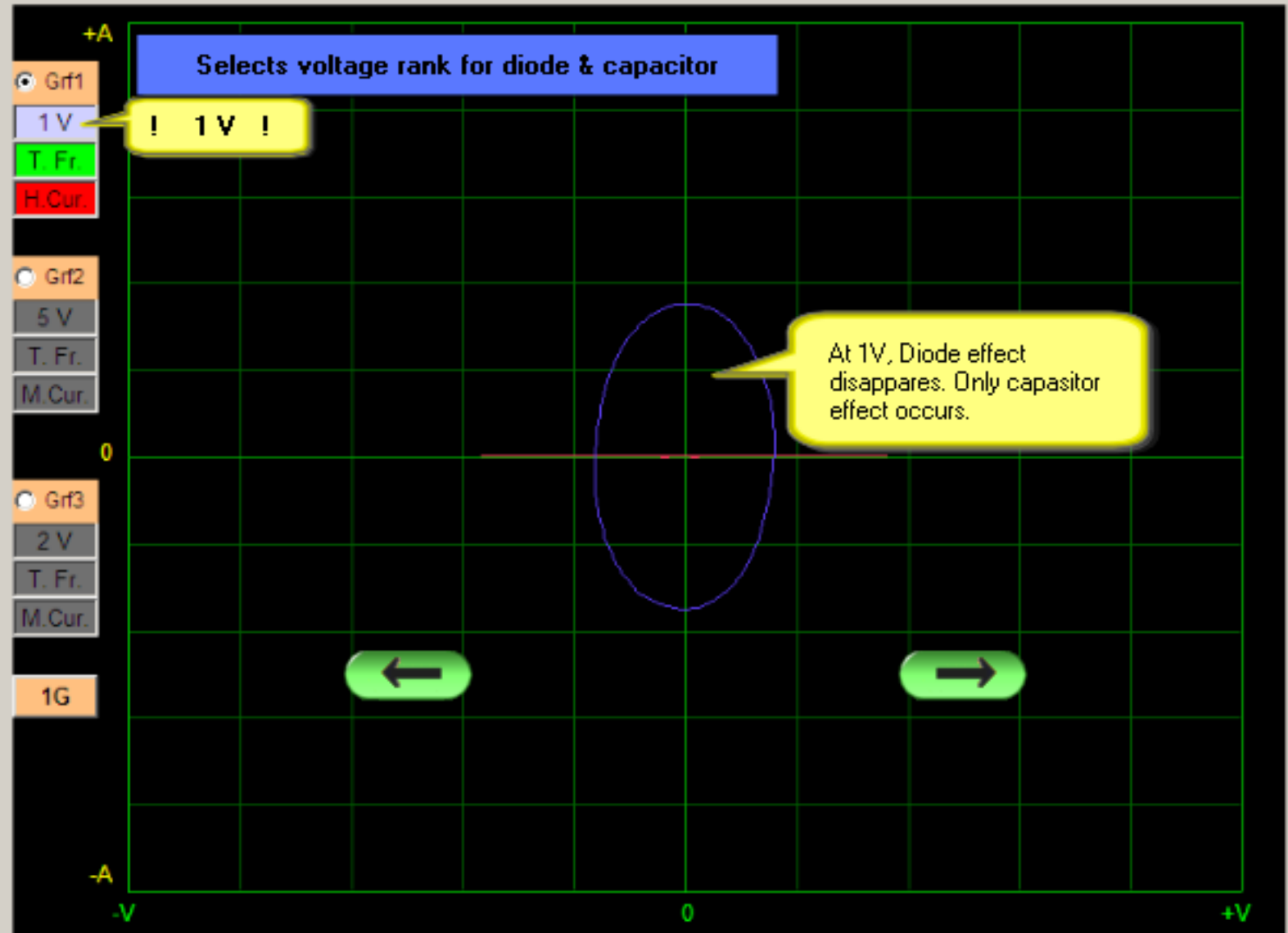
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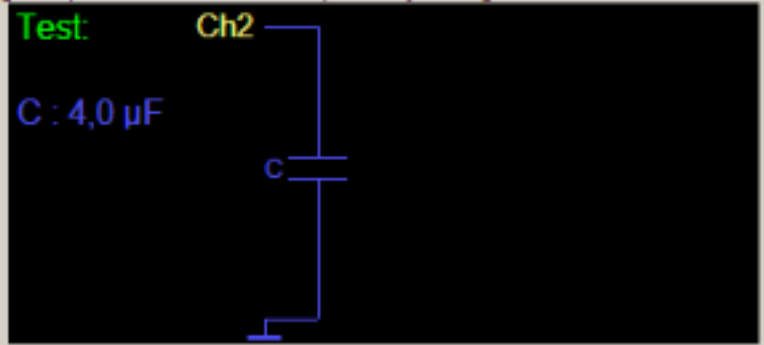
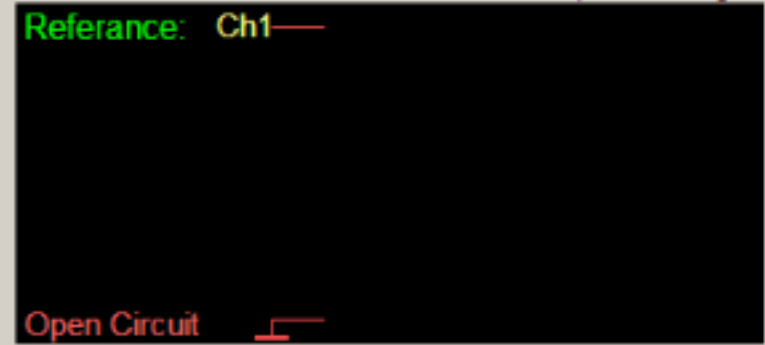
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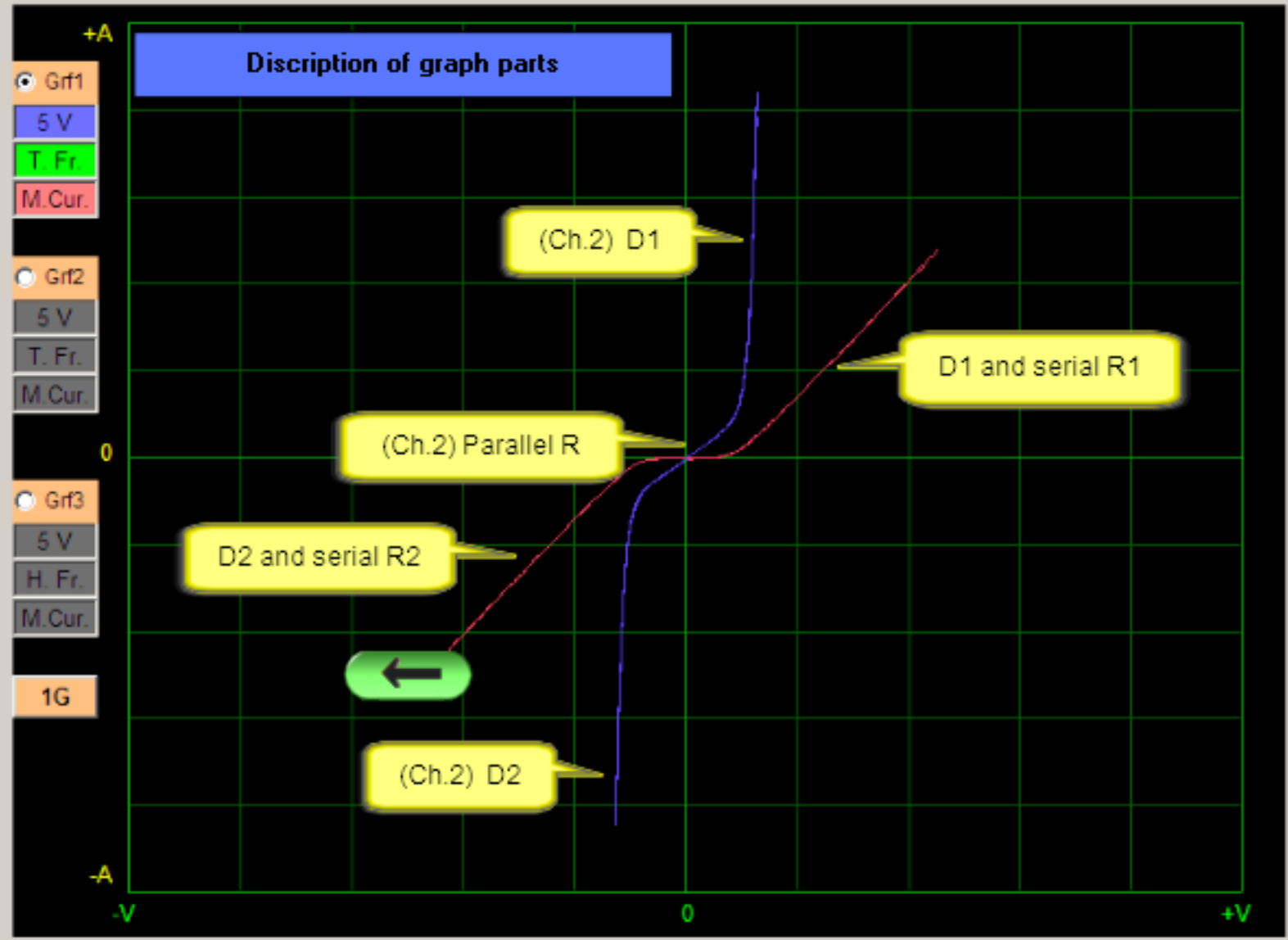
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